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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

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Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	276480
Number of I/O	119
Number of Gates	1500000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/m1afs1500-fg256i

Email: info@E-XFL.COM

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VersaNet Timing Characteristics

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are dependent upon I/O standard, and the clock may be driven and conditioned internally by the CCC module. Table 2-5, Table 2-6, Table 2-7, and Table 2-8 on page 2-17 present minimum and maximum global clock delays within the device Minimum and maximum delays are measured with minimum and maximum loading, respectively.

Timing Characteristics

 Table 2-5 • AFS1500 Global Resource Timing

 Commercial Temperature Range Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	-2		-1		Std.		Unito
		Min. ¹	Max. ²	Min. ¹	Max. ²	Min. ¹	Max. ²	Units
t _{RCKL}	Input Low Delay for Global Clock	1.53	1.75	1.74	1.99	2.05	2.34	ns
t _{RCKH}	Input High Delay for Global Clock	1.53	1.79	1.75	2.04	2.05	2.40	ns
t _{RCKMPWH}	Minimum Pulse Width High for Global Clock							ns
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock							ns
t _{RCKSW}	Maximum Skew for Global Clock		0.26		0.29		0.34	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element located in a lightly loaded row (single element is connected to the global net).

2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element located in a fully loaded row (all available flip-flops are connected to the global net in the row).

3. For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.

Table 2-6 • AFS600 Global Resource Timing

Commercial Temperature Range Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V

Paramotor	Description	-2		-1		Std.		Unite
Falailletei	Description		Max. ²	Min. ¹	Max. ²	Min. ¹	Max. ²	Units
t _{RCKL}	Input Low Delay for Global Clock	1.27	1.49	1.44	1.70	1.69	2.00	ns
t _{RCKH}	Input High Delay for Global Clock	1.26	1.54	1.44	1.75	1.69	2.06	ns
t _{RCKMPWH}	H Minimum Pulse Width High for Global Clock							ns
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock							ns
t _{RCKSW}	Maximum Skew for Global Clock		0.27		0.31		0.36	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element located in a lightly loaded row (single element is connected to the global net).

2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element located in a fully loaded row (all available flip-flops are connected to the global net in the row).

3. For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.

Crystal Oscillator

The Crystal Oscillator (XTLOSC) is source that generates the clock from an external crystal. The output of XTLOSC CLKOUT signal can be selected as an input to the PLL. Refer to the "Clock Conditioning Circuits" section for more details. The XTLOSC can operate in normal operations and Standby mode (RTC is running and 1.5 V is not present).

In normal operation, the internal FPGA_EN signal is '1' as long as 1.5 V is present for VCC. As such, the internal enable signal, XTL_EN, for Crystal Oscillator is enabled since FPGA_EN is asserted. The XTL_MODE has the option of using MODE or RTC_MODE, depending on SELMODE.

During Standby, 1.5 V is not available, as such, and FPGA_EN is '0'. SELMODE must be asserted in order for XTL_EN to be enabled; hence XTL_MODE relies on RTC_MODE. SELMODE and RTC_MODE must be connected to RTCXTLSEL and RTCXTLMODE from the AB respectively for correct operation during Standby (refer to the "Real-Time Counter System" section on page 2-31 for a detailed description).

The Crystal Oscillator can be configured in one of four modes:

- RC network, 32 KHz to 4 MHz
- Low gain, 32 to 200 KHz
- Medium gain, 0.20 to 2.0 MHz
- High gain, 2.0 to 20.0 MHz

In RC network mode, the XTAL1 pin is connected to an RC circuit, as shown in Figure 2-16 on page 2-18. The XTAL2 pin should be left floating. The RC value can be chosen based on Figure 2-18 for any desired frequency between 32 KHz and 4 MHz. The RC network mode can also accommodate an external clock source on XTAL1 instead of an RC circuit.

In Low gain, Medium gain, and High gain, an external crystal component or ceramic resonator can be added onto XTAL1 and XTAL2, as shown in Figure 2-16 on page 2-18. In the case where the Crystal Oscillator block is not used, the XTAL1 pin should be connected to GND and the XTAL2 pin should be left floating.



Note: *Internal signal—does not exist in macro.

Figure 2-17 • XTLOSC Macro

Flash Memory Block Characteristics



Figure 2-44 • Reset Timing Diagram

Table 2-25 • Flash Memory Block TimingCommercial Temperature Range Conditions: TJ = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	-2	-1	Std.	Units
	Clock-to-Q in 5-cycle read mode of the Read Data	7.99	9.10	10.70	ns
^I CLK2RD Clock-to-Q in 6-cycle read mode of the Read Data		5.03	5.73	6.74	ns
Clock-to-Q in 5-cycle read mode of BUSY		4.95	5.63	6.62	ns
^I CLK2BUSY	Clock-to-Q in 6-cycle read mode of BUSY	4.45	5.07	5.96	ns
Clock-to-Status in 5-cycle read mode		11.24	12.81	15.06	ns
^I CLK2STATUS	Clock-to-Status in 6-cycle read mode		5.10	6.00	ns
t _{DSUNVM}	Data Input Setup time for the Control Logic	1.92	2.19	2.57	ns
t _{DHNVM}	Data Input Hold time for the Control Logic	0.00	0.00	0.00	ns
t _{ASUNVM}	Address Input Setup time for the Control Logic	2.76	3.14	3.69	ns
t _{AHNVM}	Address Input Hold time for the Control Logic	0.00	0.00	0.00	ns
t _{SUDWNVM}	Data Width Setup time for the Control Logic	1.85	2.11	2.48	ns
t _{HDDWNVM}	Data Width Hold time for the Control Logic	0.00	0.00	0.00	ns
t _{SURENNVM}	Read Enable Setup time for the Control Logic	3.85	4.39	5.16	ns
t _{HDRENNVM}	Read Enable Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUWENNVM}	Write Enable Setup time for the Control Logic	2.37	2.69	3.17	ns
t _{HDWENNVM}	Write Enable Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUPROGNVM}	Program Setup time for the Control Logic	2.16	2.46	2.89	ns
t _{HDPROGNVM}	Program Hold time for the Control Logic	0.00	0.00	0.00	ns
t _{SUSPAREPAGE}	SparePage Setup time for the Control Logic	3.74	4.26	5.01	ns
t _{HDSPAREPAGE}	SparePage Hold time for the Control Logic	0.00	0.00	0.00	ns
t _{SUAUXBLK}	Auxiliary Block Setup Time for the Control Logic	3.74	4.26	5.00	ns
t _{HDAUXBLK}	Auxiliary Block Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SURDNEXT}	ReadNext Setup Time for the Control Logic	2.17	2.47	2.90	ns
t _{HDRDNEXT}	ReadNext Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUERASEPG}	Erase Page Setup Time for the Control Logic	3.76	4.28	5.03	ns
t _{HDERASEPG}	Erase Page Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUUNPROTECTPG}	Unprotect Page Setup Time for the Control Logic	2.01	2.29	2.69	ns
t _{HDUNPROTECTPG}	Unprotect Page Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUDISCARDPG}	Discard Page Setup Time for the Control Logic	1.88	2.14	2.52	ns
t _{HDDISCARDPG}	Discard Page Hold Time for the Control Logic	0.00	0.00	0.00	ns
t _{SUOVERWRPRO}	Overwrite Protect Setup Time for the Control Logic	1.64	1.86	2.19	ns
t _{HDOVERWRPRO}	Overwrite Protect Hold Time for the Control Logic	0.00	0.00	0.00	ns

The following signals are used to configure the RAM4K9 memory element.

WIDTHA and WIDTHB

These signals enable the RAM to be configured in one of four allowable aspect ratios (Table 2-27).

|--|

WIDTHA1, WIDTHA0	WIDTHB1, WIDTHB0	D×W		
00	00	4k×1		
01	01	2k×2		
10	10	1k×4		
11 11 512×9				
Note: The aspect ratio settings are constant and cannot be changed on the fly.				

BLKA and BLKB

These signals are active low and will enable the respective ports when asserted. When a BLKx signal is deasserted, the corresponding port's outputs hold the previous value.

WENA and WENB

These signals switch the RAM between read and write mode for the respective ports. A Low on these signals indicates a write operation, and a High indicates a read.

CLKA and CLKB

These are the clock signals for the synchronous read and write operations. These can be driven independently or with the same driver.

PIPEA and PIPEB

These signals are used to specify pipelined read on the output. A Low on PIPEA or PIPEB indicates a nonpipelined read, and the data appears on the corresponding output in the same clock cycle. A High indicates a pipelined, read and data appears on the corresponding output in the next clock cycle.

WMODEA and WMODEB

These signals are used to configure the behavior of the output when the RAM is in write mode. A Low on these signals makes the output retain data from the previous read. A High indicates pass-through behavior, wherein the data being written will appear immediately on the output. This signal is overridden when the RAM is being read.

RESET

This active low signal resets the output to zero, disables reads and writes from the SRAM block, and clears the data hold registers when asserted. It does not reset the contents of the memory.

ADDRA and ADDRB

These are used as read or write addresses, and they are 12 bits wide. When a depth of less than 4 k is specified, the unused high-order bits must be grounded (Table 2-28).

Table 2-28 • Address Pins Unused/Used for Various Supported Bus Widths

DxW	ADDRx				
	Unused Used				
4k×1	None	[11:0]			
2k×2	[11]	[10:0]			
1k×4	[11:10]	[9:0]			
512×9	[11:9]	[8:0]			

Note: The "x" in ADDRx implies A or B.



Device Architecture

DINA and DINB

These are the input data signals, and they are nine bits wide. Not all nine bits are valid in all configurations. When a data width less than nine is specified, unused high-order signals must be grounded (Table 2-29).

DOUTA and DOUTB

These are the nine-bit output data signals. Not all nine bits are valid in all configurations. As with DINA and DINB, high-order bits may not be used (Table 2-29). The output data on unused pins is undefined.

Table 2-29 • Unused/Used Input and Output Data Pins for Various Supported Bus Widths

D×W	DINx/DOUTx				
	Unused	Used			
4k×1	[8:1]	[0]			
2k×2	[8:2]	[1:0]			
1k×4	[8:4]	[3:0]			
512×9	None	[8:0]			

Note: The "x" in DINx and DOUTx implies A or B.



RAM512X18 Description

Figure 2-49 • RAM512X18

Table 2-36 describes each pin in the Analog Block. Each function within the Analog Block will be explained in detail in the following sections.

Table 2-36 • Analog Block Pin Description

Signal Name	Number of Bits	Direction	Function	Location of Details
VAREF	1	Input/Output	Voltage reference for ADC	ADC
ADCGNDREF	1	Input	External ground reference	ADC
MODE[3:0]	4	Input	ADC operating mode	ADC
SYSCLK	1	Input	External system clock	
TVC[7:0]	8	Input	Clock divide control	ADC
STC[7:0]	8	Input	Sample time control	ADC
ADCSTART	1	Input	Start of conversion	ADC
PWRDWN	1	Input	ADC comparator power-down if 1. When asserted, the ADC will stop functioning, and the digital portion of the analog block will continue operating. This may result in invalid status flags from the analog block. Therefore, Microsemi does not recommend asserting the PWRDWN pin.	ADC
ADCRESET	1	Input	ADC resets and disables Analog Quad – active high	ADC
BUSY	1	Output	1 – Running conversion	ADC
CALIBRATE	1	Output	1 – Power-up calibration	ADC
DATAVALID	1	Output	1 – Valid conversion result	ADC
RESULT[11:0]	12	Output	Conversion result	ADC
TMSTBINT	1	Input	Internal temp. monitor strobe	ADC
SAMPLE	1	Output	 1 – An analog signal is actively being sampled (stays high during signal acquisition only) 0 – No analog signal is being sampled 	ADC
VAREFSEL	1	Input	0 = Output internal voltage reference (2.56 V) to VAREF 1 = Input external voltage reference	ADC
	_		from VAREF and ADCGNDREF	
CHNUMBER[4:0]	5	Input	Analog input channel select	Input multiplexer
ACMCLK	1	Input	ACM clock	ACM
ACMWEN	1	Input	ACM write enable – active high	ACM
ACMRESET	1	Input	ACM reset – active low	ACM
ACMWDATA[7:0]	8	Input	ACM write data	ACM
ACMRDATA[7:0]	8	Output	ACM read data	ACM
ACMADDR[7:0]	8	Input	ACM address	ACM
CMSTB0 to CMSTB9	10	Input	Current monitor strobe – 1 per quad, active high	Analog Quad



Table 2-61 details the settings available to either power down or enable the prescaler associated with the analog inputs AV, AC, and AT.

Table 2-61 • Prescaler Op Amp Power-Down Truth Table—AV (x = 0), AC (x = 1), and AT (x = 3)

Control Lines Bx[7]	Prescaler Op Amp
0	Power-down
1	Operational

Table 2-62 details the settings available to enable the Current Monitor Block associated with the AC pin.

Table 2-62 • Current Monitor Input Switch Control Truth Table—AV (x = 0)

Control Lines B0[4]	Current Monitor Input Switch
0	Off
1	On

Table 2-63 details the settings available to configure the drive strength of the gate drive when not in highdrive mode.

Table 2-63 • Low-Drive Gate Driver Current Truth Table (AG)

Control Lines B2[3]	Control Lines B2[2]	Current (µA)
0	0	1
0	1	3
1	0	10
1	1	30

Table 2-64 details the settings available to set the polarity of the gate driver (either p-channel- or n-channel-type devices).

Table 2-64 • Gate Driver Polarity Truth Table (AG)

Control Lines B2[6]	Gate Driver Polarity
0	Positive
1	Negative

Table 2-65 details the settings available to turn on the Gate Driver and set whether high-drive mode is on or off.

Table 2-65 • Gate Driver Control Truth Table (AG)

Control Lines B2[7]	GDON	Gate Driver
0	0	Off
0	1	Low drive on
1	0	Off
1	1	High drive on

Table 2-66 details the settings available to turn on and off the chip internal temperature monitor.

Note: For the internal temperature monitor to function, Bit 0 of Byte 2 for all 10 Quads must be set.

Table 2-66 • Internal Temperature Monitor Control Truth Table

Control Lines B2[0]	PDTMB	Chip Internal Temperature Monitor
0	0	Off
1	1	On



Temporary overshoots are allowed according to Table 3-4 on page 3-4.



Figure 2-103 • Solution 1

Solution 2

The board-level design must ensure that the reflected waveform at the pad does not exceed limits provided in Table 3-4 on page 3-4. This is a long-term reliability requirement.

This scheme will also work for a 3.3 V PCI/PCI-X configuration, but the internal diode should not be used for clamping, and the voltage must be limited by the external resistors and Zener, as shown in Figure 2-104. Relying on the diode clamping would create an excessive pad DC voltage of 3.3 V + 0.7 V = 4 V.



Figure 2-104 • Solution 2





Figure 2-114 • Naming Conventions of Fusion Devices with Four I/O Banks



Device Architecture

Table 2-92 • Summary of I/O Timing Characteristics – Software Default SettingsCommercial Temperature Range Conditions: TJ = 70°C, Worst-Case VCC = 1.425 V,Worst-Case VCCI = I/O Standard DependentApplicable to Pro I/Os

I/O Standard	Drive Strength (mA)	Slew Rate	Capacitive Load (pF)	External Resistor (Ohm)	t DOUT	top	t _{DIN}	tpy	t _{PY} S	teour	tzı	tzh	tız	tHz	tzıs	tzHS	Units
3.3 V LVTTL/ 3.3 V LVCMOS	12 mA	High	35	-	0.49	2.74	0.03	0.90	1.17	0.32	2.79	2.14	2.45	2.70	4.46	3.81	ns
2.5 V LVCMOS	12 mA	High	35	-	0.49	2.80	0.03	1.13	1.24	0.32	2.85	2.61	2.51	2.61	4.52	4.28	ns
1.8 V LVCMOS	12 mA	High	35	_	0.49	2.83	0.03	1.08	1.42	0.32	2.89	2.31	2.79	3.16	4.56	3.98	ns
1.5 V LVCMOS	12 mA	High	35	_	0.49	3.30	0.03	1.27	1.60	0.32	3.36	2.70	2.96	3.27	5.03	4.37	ns
3.3 V PCI	Per PCI spec	High	10	25 ²	0.49	2.09	0.03	0.78	1.25	0.32	2.13	1.49	2.45	2.70	3.80	3.16	ns
3.3 V PCI-X	Per PCI-X spec	High	10	25 ²	0.49	2.09	0.03	0.77	1.17	0.32	2.13	1.49	2.45	2.70	3.80	3.16	ns
3.3 V GTL	20 mA	High	10	25	0.49	1.55	0.03	2.19	_	0.32	1.52	1.55	0.00	0.00	3.19	3.22	ns
2.5 V GTL	20 mA	High	10	25	0.49	1.59	0.03	1.83	-	0.32	1.61	1.59	0.00	0.00	3.28	3.26	ns
3.3 V GTL+	35 mA	High	10	25	0.49	1.53	0.03	1.19	_	0.32	1.56	1.53	0.00	0.00	3.23	3.20	ns
2.5 V GTL+	33 mA	High	10	25	0.49	1.65	0.03	1.13	_	0.32	1.68	1.57	0.00	0.00	3.35	3.24	ns
HSTL (I)	8 mA	High	20	50	0.49	2.37	0.03	1.59	_	0.32	2.42	2.35	0.00	0.00	4.09	4.02	ns
HSTL (II)	15 mA	High	20	25	0.49	2.26	0.03	1.59	_	0.32	2.30	2.03	0.00	0.00	3.97	3.70	ns
SSTL2 (I)	17 mA	High	30	50	0.49	1.59	0.03	1.00	_	0.32	1.62	1.38	0.00	0.00	3.29	3.05	ns
SSTL2 (II)	21 mA	High	30	25	0.49	1.62	0.03	1.00	-	0.32	1.65	1.32	0.00	0.00	3.32	2.99	ns
SSTL3 (I)	16 mA	High	30	50	0.49	1.72	0.03	0.93	-	0.32	1.75	1.37	0.00	0.00	3.42	3.04	ns
SSTL3 (II)	24 mA	High	30	25	0.49	1.54	0.03	0.93	_	0.32	1.57	1.25	0.00	0.00	3.24	2.92	ns
LVDS	24 mA	High	_	_	0.49	1.57	0.03	1.36	_	_	_	_	_	_	_	_	ns
LVPECL	24 mA	High	-	-	0.49	1.60	0.03	1.22	1	_	_	-	-	_	_	-	ns

Notes:

1. For specific junction temperature and voltage-supply levels, refer to Table 3-6 on page 3-7 for derating values.

2. Resistance is used to measure I/O propagation delays as defined in PCI specifications. See Figure 2-123 on page 2-197 for connectivity. This resistor is not required during normal operation.

Table 2-114 • 2.5 V LVCMOS Low Slew

Commercial Temperature Range Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V Applicable to Advanced I/Os

Drive Strength	Speed Grade	toour	top	toin	tev	teour	tzı	t≂⊔	tı z	tu-z	tzı e	tzue	Units
4 mA	Std.	0.66	11.40	0.04	1.31	0.43	11.22	- <u>г</u> н 11.40	2.68	2.20	13.45	13.63	ns
	-1	0.56	9.69	0.04	1.11	0.36	9.54	9.69	2.28	1.88	11.44	11.60	ns
	-2	0.49	8.51	0.03	0.98	0.32	8.38	8.51	2.00	1.65	10.05	10.18	ns
8 mA	Std.	0.66	7.96	0.04	1.31	0.43	8.11	7.81	3.05	2.89	10.34	10.05	ns
	-1	0.56	6.77	0.04	1.11	0.36	6.90	6.65	2.59	2.46	8.80	8.55	ns
	-2	0.49	5.94	0.03	0.98	0.32	6.05	5.84	2.28	2.16	7.72	7.50	ns
12 mA	Std.	0.66	6.18	0.04	1.31	0.43	6.29	5.92	3.30	3.32	8.53	8.15	ns
	-1	0.56	5.26	0.04	1.11	0.36	5.35	5.03	2.81	2.83	7.26	6.94	ns
	-2	0.49	4.61	0.03	0.98	0.32	4.70	4.42	2.47	2.48	6.37	6.09	ns
16 mA	Std.	0.66	6.18	0.04	1.31	0.43	6.29	5.92	3.30	3.32	8.53	8.15	ns
	-1	0.56	5.26	0.04	1.11	0.36	5.35	5.03	2.81	2.83	7.26	6.94	ns
	-2	0.49	4.61	0.03	0.98	0.32	4.70	4.42	2.47	2.48	6.37	6.09	ns
24 mA	Std.	0.66	6.18	0.04	1.31	0.43	6.29	5.92	3.30	3.32	8.53	8.15	ns
	-1	0.56	5.26	0.04	1.11	0.36	5.35	5.03	2.81	2.83	7.26	6.94	ns
	-2	0.49	4.61	0.03	0.98	0.32	4.70	4.42	2.47	2.48	6.37	6.09	ns

Note: For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.

SSTL2 Class II

Stub-Speed Terminated Logic for 2.5 V memory bus standard (JESD8-9). Fusion devices support Class II. This provides a differential amplifier input buffer and a push-pull output buffer.

SSTL2 Class II		VIL	VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
18 mA	-0.3	VREF – 0.2	VREF + 0.2	3.6	0.35	VCCI – 0.43	18	18	124	169	10	10

Table 2-159 • Minimum and Maximum DC Input and Output Levels

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where –0.3 V < VIN < VIL.

2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.

3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.

4. Currents are measured at 85°C junction temperature.



Figure 2-131 • AC Loading

Table 2-160 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF – 0.2	VREF + 0.2	1.25	1.25	1.25	30

Note: *Measuring point = Vtrip. See Table 2-90 on page 2-166 for a complete table of trip points.

Timing Characteristics

Table 2-161 • SSTL 2 Class II Commercial Temperature Range Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V, VREF = 1.25 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{zH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{zHS}	Units
Std.	0.66	2.17	0.04	1.33	0.43	2.21	1.77			4.44	4.01	ns
-1	0.56	1.84	0.04	1.14	0.36	1.88	1.51			3.78	3.41	ns
-2	0.49	1.62	0.03	1.00	0.32	1.65	1.32			3.32	2.99	ns

Note: For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.



Fully Registered I/O Buffers with Synchronous Enable and Asynchronous Clear

Figure 2-138 • Timing Model of the Registered I/O Buffers with Synchronous Enable and Asynchronous Clear



The 1.76 W power is less than the required 3.00 W. The design therefore requires a heat sink, or the airflow where the device is mounted should be increased. The design's total junction-to-air thermal resistance requirement can be estimated by EQ 7:

$$\theta_{ja(total)} = \frac{T_J - T_A}{P} = \frac{100^{\circ}C - 70^{\circ}C}{3.00 \text{ W}} = 10.00^{\circ}\text{C/W}$$

Determining the heat sink's thermal performance proceeds as follows:

$$\theta_{\text{JA(TOTAL)}} = \theta_{\text{JC}} + \theta_{\text{CS}} + \theta_{\text{SA}}$$

EQ 8

EQ 7

where

- $\theta_{JA} = 0.37^{\circ}C/W$
 - Thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

 θ_{SA} = Thermal resistance of the heat sink in °C/W

$$\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$$

EQ 9

$$\theta_{SA} = 13.33^{\circ}C/W - 8.28^{\circ}C/W - 0.37^{\circ}C/W = 5.01^{\circ}C/W$$

A heat sink with a thermal resistance of 5.01°C/W or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with increased airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Microsemi FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device.

Note: The junction-to-air and junction-to-board thermal resistances are based on JEDEC standard (JESD-51) and assumptions made in building the model. It may not be realized in actual application and therefore should be used with a degree of caution. Junction-to-case thermal resistance assumes that all power is dissipated through the case.

Temperature and Voltage Derating Factors

Table 3-7 • Temperature and Voltage Derating Factors for Timing Delays
(normalized to $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V)

Array Voltage	Junction Temperature (°C)										
VCC (V)	–40°C	0°C	25°C	70°C	85°C	100°C					
1.425	0.88	0.93	0.95	1.00	1.02	1.05					
1.500	0.83	0.88	0.90	0.95	0.96	0.99					
1.575	0.80	0.85	0.87	0.91	0.93	0.96					

	QN180		QN180						
Pin Number	AFS090 Function	AFS250 Function	Pin Number	AFS090 Function	AFS250 Function				
B9	XTAL2	XTAL2	B45	GBA2/IO31PDB1V0	GBA2/IO40PDB1V0				
B10	GEA0/IO44NDB3V0	GFA0/IO66NDB3V0	B46	GNDQ	GNDQ				
B11	GEB2/IO42PDB3V0	IO60NDB3V0	B47	GBA1/IO30RSB0V0	GBA0/IO38RSB0V0				
B12	VCC	VCC	B48	GBB1/IO28RSB0V0	GBC1/IO35RSB0V0				
B13	VCCNVM	VCCNVM	B49	VCC	VCC				
B14	VCC15A	VCC15A	B50	GBC0/IO25RSB0V0	IO31RSB0V0				
B15	NCAP	NCAP	B51	IO23RSB0V0	IO28RSB0V0				
B16	VCC33N	VCC33N	B52	IO20RSB0V0	IO25RSB0V0				
B17	GNDAQ	GNDAQ	B53	VCC	VCC				
B18	AC0	AC0	B54	IO11RSB0V0	IO14RSB0V0				
B19	AT0	AT0	B55	IO08RSB0V0	IO11RSB0V0				
B20	AT1	AT1	B56	GAC1/IO05RSB0V0	IO08RSB0V0				
B21	AV1	AV1	B57	VCCIB0	VCCIB0				
B22	AC2	AC2	B58	GAB0/IO02RSB0V0	GAC0/IO04RSB0V0				
B23	ATRTN1	ATRTN1	B59	GAA0/IO00RSB0V0	GAA1/IO01RSB0V0				
B24	AG3	AG3	B60	VCCPLA	VCCPLA				
B25	AV3	AV3	C1	NC	NC				
B26	AG4	AG4	C2	NC	VCCIB3				
B27	ATRTN2	ATRTN2	C3	GND	GND				
B28	NC	AC5	C4	NC	GFC2/IO69PPB3V0				
B29	VCC33A	VCC33A	C5	GFC1/IO49PDB3V0	GFC1/IO68PDB3V0				
B30	VAREF	VAREF	C6	GFA0/IO47NPB3V0	GFB0/IO67NPB3V0				
B31	PUB	PUB	C7	VCCIB3	NC				
B32	PTEM	PTEM	C8	GND	GND				
B33	GNDNVM	GNDNVM	C9	GEA1/IO44PDB3V0	GFA1/IO66PDB3V0				
B34	VCC	VCC	C10	GEA2/IO42NDB3V0	GEC2/IO60PDB3V0				
B35	ТСК	ТСК	C11	NC	GEA2/IO58PSB3V0				
B36	TMS	TMS	C12	NC	NC				
B37	TRST	TRST	C13	GND	GND				
B38	GDB2/IO41PSB1V0	GDA2/IO55PSB1V0	C14	NC	NC				
B39	GDC0/IO38NDB1V0	GDB0/IO53NDB1V0	C15	NC	NC				
B40	VCCIB1	VCCIB1	C16	GNDA	GNDA				
B41	GCA1/IO36PDB1V0	GCA1/IO49PDB1V0	C17	NC	NC				
B42	GCC0/IO34NDB1V0	GCC0/IO47NDB1V0	C18	NC	NC				
B43	GCB2/IO33PSB1V0	GBC2/IO42PSB1V0	C19	NC	NC				
B44	VCC	VCC	C20	NC	NC				

Microsemi

Package Pin Assignments

	FG676		FG676		FG676
Pin Number	AFS1500 Function	Pin Number	AFS1500 Function	Pin Number	AFS1500 Function
A1	NC	AA11	AV2	AB21	PTBASE
A2	GND	AA12	GNDA	AB22	GNDNVM
A3	NC	AA13	AV3	AB23	VCCNVM
A4	NC	AA14	AV6	AB24	VPUMP
A5	GND	AA15	GNDA	AB25	NC
A6	NC	AA16	AV7	AB26	GND
A7	NC	AA17	AV8	AC1	NC
A8	GND	AA18	GNDA	AC2	NC
A9	IO17NDB0V2	AA19	AV9	AC3	NC
A10	IO17PDB0V2	AA20	VCCIB2	AC4	GND
A11	GND	AA21	IO68PPB2V0	AC5	VCCIB4
A12	IO18NDB0V2	AA22	ТСК	AC6	VCCIB4
A13	IO18PDB0V2	AA23	GND	AC7	PCAP
A14	IO20NDB0V2	AA24	IO76PPB2V0	AC8	AG0
A15	IO20PDB0V2	AA25	VCCIB2	AC9	GNDA
A16	GND	AA26	NC	AC10	AG1
A17	IO21PDB0V2	AB1	GND	AC11	AG2
A18	IO21NDB0V2	AB2	NC	AC12	GNDA
A19	GND	AB3	GEC2/IO87PDB4V0	AC13	AG3
A20	IO39NDB1V2	AB4	IO87NDB4V0	AC14	AG6
A21	IO39PDB1V2	AB5	GEA2/IO85PDB4V0	AC15	GNDA
A22	GND	AB6	IO85NDB4V0	AC16	AG7
A23	NC	AB7	NCAP	AC17	AG8
A24	NC	AB8	AC0	AC18	GNDA
A25	GND	AB9	VCC33A	AC19	AG9
A26	NC	AB10	AC1	AC20	VAREF
AA1	NC	AB11	AC2	AC21	VCCIB2
AA2	VCCIB4	AB12	VCC33A	AC22	PTEM
AA3	IO93PDB4V0	AB13	AC3	AC23	GND
AA4	GND	AB14	AC6	AC24	NC
AA5	IO93NDB4V0	AB15	VCC33A	AC25	NC
AA6	GEB2/IO86PDB4V0	AB16	AC7	AC26	NC
AA7	IO86NDB4V0	AB17	AC8	AD1	NC
AA8	AV0	AB18	VCC33A	AD2	NC
AA9	GNDA	AB19	AC9	AD3	GND
AA10	AV1	AB20	ADCGNDREF	AD4	NC

Fusion Family of Mixed Signal FPGAs

	FG676		FG676		FG676
Pin Number	AFS1500 Function	Pin Number	AFS1500 Function	Pin Number	AFS1500 Function
G13	IO22NDB1V0	H23	IO50NDB2V0	K7	IO114PDB4V0
G14	IO22PDB1V0	H24	IO51PDB2V0	K8	IO117NDB4V0
G15	GND	H25	NC	K9	GND
G16	IO32PPB1V1	H26	GND	K10	VCC
G17	IO36NPB1V2	J1	NC	K11	VCCIB0
G18	VCCIB1	J2	VCCIB4	K12	GND
G19	GND	J3	IO115PDB4V0	K13	VCCIB0
G20	IO47NPB2V0	J4	GND	K14	VCCIB1
G21	IO49PDB2V0	J5	IO116NDB4V0	K15	GND
G22	VCCIB2	J6	IO116PDB4V0	K16	VCCIB1
G23	IO46NDB2V0	J7	VCCIB4	K17	GND
G24	GBC2/IO46PDB2V0	J8	IO117PDB4V0	K18	GND
G25	IO48NPB2V0	J9	VCCIB4	K19	IO53NDB2V0
G26	NC	J10	GND	K20	IO57PDB2V0
H1	GND	J11	IO06NDB0V1	K21	GCA2/IO59PDB2V0
H2	NC	J12	IO06PDB0V1	K22	VCCIB2
H3	IO118NDB4V0	J13	IO16NDB0V2	K23	IO54NDB2V0
H4	IO118PDB4V0	J14	IO16PDB0V2	K24	IO54PDB2V0
H5	IO119NPB4V0	J15	IO28NDB1V1	K25	NC
H6	IO124NDB4V0	J16	IO28PDB1V1	K26	NC
H7	GND	J17	GND	L1	GND
H8	VCOMPLA	J18	IO38PPB1V2	L2	NC
H9	VCCPLA	J19	IO53PDB2V0	L3	IO112PPB4V0
H10	VCCIB0	J20	VCCIB2	L4	IO113NDB4V0
H11	IO12NDB0V1	J21	IO52PDB2V0	L5	GFB2/IO109PDB4V0
H12	IO12PDB0V1	J22	IO52NDB2V0	L6	GFA2/IO110PDB4V0
H13	VCCIB0	J23	GND	L7	IO112NPB4V0
H14	VCCIB1	J24	IO51NDB2V0	L8	IO104PDB4V0
H15	IO30NDB1V1	J25	VCCIB2	L9	IO111PDB4V0
H16	IO30PDB1V1	J26	NC	L10	VCCIB4
H17	VCCIB1	K1	NC	L11	GND
H18	IO36PPB1V2	K2	NC	L12	VCC
H19	IO38NPB1V2	K3	IO115NDB4V0	L13	GND
H20	GND	K4	IO113PDB4V0	L14	VCC
H21	IO49NDB2V0	K5	VCCIB4	L15	GND
H22	IO50PDB2V0	K6	IO114NDB4V0	L16	VCC
				<u>-</u>	



Revision	Changes	Page
Advance v1.5 (continued)	This bullet was added to the "Integrated A/D Converter (ADC) and Analog I/O" section: ADC Accuracy is Better than 1%	I
	In the "Integrated Analog Blocks and Analog I/Os" section, ±4 LSB was changed to 0.72. The following sentence was deleted:	1-4
	The input range for voltage signals is from -12 V to $+12$ V with full-scale output values from 0.125 V to 16 V.	l
	In addition, 2°C was changed to 3°C:	1
	"One analog input in each quad can be connected to an external temperature monitor diode and achieves detection accuracy of ±3°C."	1
	The following sentence was deleted:	1
	The input range for voltage signals is from -12 V to $+12$ V with full-scale output values from 0.125 V to 16 V.	1
	The title of the datasheet changed from Actel Programmable System Chips to Actel Fusion Mixed Signal FPGAs. In addition, all instances of programmable system chip were changed to mixed signal FPGA.	N/A
Advance v1.4 (July 2008)	In Table 3-8 · Quiescent Supply Current Characteristics (IDDQ)1, footnote references were updated for I_{DC2} and I_{DC3} . Footnote 3 and 4 were updated and footnote 5 is new.	3-11
Advance v1 3	The "ADC Description" section was significantly updated. Please review carefully	2-102
(July 2008)		
Advance v1.2 (May 2008)	Table 2-25 • Flash Memory Block Timing was significantly updated.	2-55
	The "V _{AREF} Analog Reference Voltage" pin description section was significantly update. Please review it carefully.	2-226
	Table 2-45 • ADC Interface Timing was significantly updated.	2-110
	Table 2-56 • Direct Analog Input Switch Control Truth Table—AV ($x = 0$), AC ($x = 1$), and AT ($x = 3$) was significantly updated.	2-131
	The following sentence was deleted from the "Voltage Monitor" section:	2-86
	The Analog Quad inputs are tolerant up to 12 V + 10%.	l
	The "180-Pin QFN" figure was updated. D1 to D4 are new and the figure was changed to bottom view. The note below the figure is new.	3-3
Advance v1.1 (May 2008)	The following text was incorrect and therefore deleted:	2-204
	VCC33A Analog Power Filter	1
	Analog power pin for the analog power supply low-pass filter. An external 100 pF capacitor should be connected between this pin and ground.	l
	There is still a description of V _{CC33A} on page 2-224.	L

Fusion Family of Mixed Signal FPGAs

Revision	Changes	Page
Advance v0.6 (continued)	The "Analog-to-Digital Converter Block" section was updated with the following statement: "All results are MSB justified in the ADC."	2-99
	The information about the ADCSTART signal was updated in the "ADC Description" section.	2-102
	Table 2-46 · Analog Channel Specifications was updated.	2-118
	Table 2-47 · ADC Characteristics in Direct Input Mode was updated.	2-121
	Table 2-51 • ACM Address Decode Table for Analog Quad was updated.	2-127
	In Table 2-53 • Analog Quad ACM Byte Assignment, the Function and Default Setting for Bit 6 in Byte 3 was updated.	2-130
	The "Introduction" section was updated to include information about digital inputs, outputs, and bibufs.	2-133
	In Table 2-69 • Fusion Pro I/O Features, the programmable delay descriptions were updated for the following features:	2-137
	Single-ended receiver	
	Voltage-referenced differential receiver	
	The "liker I/O Naming Convention" section was undeted to include "V/" and "r"	2 150
	descriptions	2-159
	The "VCC33PMP Analog Power Supply (3.3 V)" section was updated to include information about avoiding high current draw.	2-224
	The "VCCNVM Flash Memory Block Power Supply (1.5 V)" section was updated to include information about avoiding high current draw.	2-224
	The "VMVx I/O Supply Voltage (quiet)" section was updated to include this statement: VMV and VCCI must be connected to the same power supply and V_{CCI} pins within a given I/O bank.	2-185
	The "PUB Push Button" section was updated to include information about leaving the pin floating if it is not used.	2-228
	The "PTBASE Pass Transistor Base" section was updated to include information about leaving the pin floating if it is not used.	2-228
	The "PTEM Pass Transistor Emitter" section was updated to include information about leaving the pin floating if it is not used.	2-228
	The heading was incorrect in the "208-Pin PQFP" table. It should be AFS250 and not AFS090.	3-8